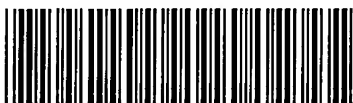


**Search Notes**

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10/519,521

Examiner

John P. Sheehan

Applicant(s)/Patent under  
Reexamination

CHOI ET AL.

Art Unit

1742

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
PG Pub	Search	1/8/2007	JPS

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	1/8/2007	JPS
PALM Inventor Name Search	1/8/2007	JPS